

512K X 16, 1 MEG X 8 CMOS Mask Programmable ROM

FEATURES

- Access time: 200ns max.
- Low Power dissipation:
 - 275mW max. (Active)
 - 5.5mW max. (Standby, TTL input level)
 - 275μW max. (Standby, CMOS input level)
- Fully static operation, no clock required
- Automatic power down (\overline{CE})
- Complete TTL compatibility
- EPROMs accepted as program data input
- Organization (selectable by \overline{BYTE} pin):
 - 524,288 words x 16 bits
 - 1,048,576 words x 8 bits
- 42 pin DIP package
- 64 pin Quad Flat package

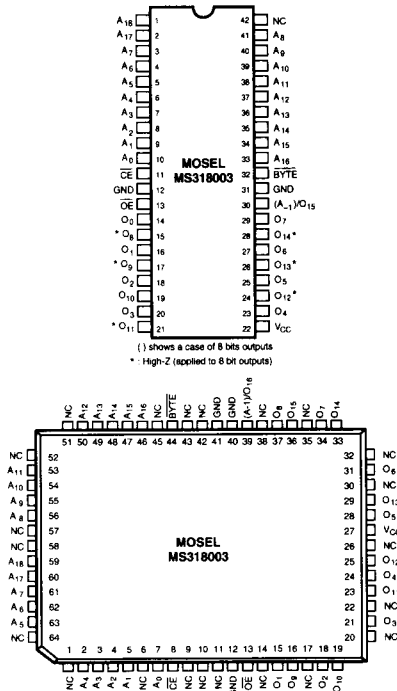
DESCRIPTION

The MOSEL MS318003 is a CMOS Si-gate mask-programmable static read only memory organized as 524,288 words by 16 bits, or 1,048,576 words by 8 bits.

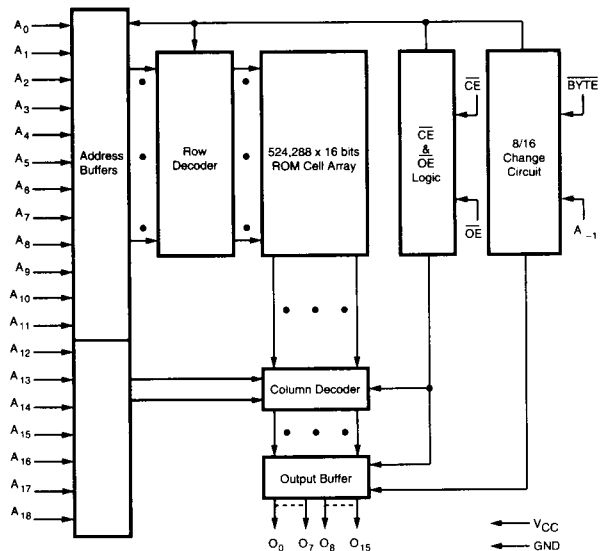
The MS318003 has TTL compatible I/O three state output level with full-static operation (i.e. no need of clock signal) and single +5V power supply. Also, the MS318003 is designed for applications such as character generator or program storage which require large memory capacity and high-speed/low-power operation.

Memory output organization of MS318003 is selectable between 16 bits and 8 bits. (ex. The system using 8 bit CPU and 16 bit CPU can use common data from ROM.)

PIN CONFIGURATIONS



BLOCK DIAGRAM



MS318003

PIN DESCRIPTIONS

| SYMBOL | FUNCTION |
|----------------------------------|--|
| A ₀ - A ₁₈ | Address Input |
| O ₀ - O ₁₅ | Data Output |
| GND | Ground |
| V _{CC} | Power Supply |
| NC | No Connection |
| \overline{CE} | Chip Enable |
| \overline{OE} | Output Enable |
| \overline{BYTE} | Selects 16 or 8 bit Data Out |
| A ₋₁ | Address Input (8 bit Data select out only) |

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

| | |
|------------------------------------|--------------------------------|
| Temperature Under Bias | -10°C to +85°C |
| Storage Temperature | -45°C to +125°C |
| Supply Voltage to Ground Potential | -0.3V to +7.0V |
| Applied Output Voltage | -0.5V to V _{CC} +0.5V |
| Applied Input Voltage | -0.5V to V _{CC} +0.5V |

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not recommended. Exposure to ABSOLUTE MAXIMUM RATINGS for extended periods may affect device reliability.

OPERATING RANGE

| RANGE | TEMPERATURE | V _{CC} |
|------------|--------------|-----------------|
| Commercial | 0°C to +70°C | 5V ± 10% |

DC ELECTRICAL CHARACTERISTICS (over the commercial operating range)

| PARAMETER NAME | PARAMETER | TEST CONDITIONS | MS318003 | | UNITS |
|--------------------|---|---|----------|----------------------|-------|
| | | | MIN. | MAX. | |
| V _{IL} | Input Low Voltage | | -0.3 | 0.8 | V |
| V _{IH} | Input High Voltage | | 2.2 | V _{CC} +0.3 | V |
| I _{IL} | Input Leakage Current | V _{IN} =0V to V _{CC} | -10 | 10 | μA |
| I _{OL} | Output Leakage Current | \overline{CE} =V _{IH} , \overline{OE} =V _{IH} | -10 | 10 | μA |
| V _{OL} | Output Low Voltage | I _{OL} =2.1mA | - | 0.4 | V |
| V _{OH} | Output High Voltage | I _{OH} =-400μA | 2.4 | - | V |
| I _{CC} | Operating Power Supply Current ⁽¹⁾ | \overline{CE} =V _{IL} , Min Cycle | - | 50 | mA |
| I _{CCSB} | Standby Power Supply Current | \overline{CE} =V _{IH} | - | 1 | mA |
| I _{CCSB1} | Super Standby Power Supply Current | \overline{CE} =V _{IH} =V _{CC} , V _{IN} =GND or V _{CC} | - | 50 | μA |

1. Measured with device selected and outputs unloaded.

CAPACITANCE (Ta=25°C, f=1.0MHz)⁽¹⁾

| SYMBOL | PARAMETER | CONDITION | MAX. | UNIT |
|--------|--------------------|-------------------------|------|------|
| CI | Input Capacitance | V _{IN/OUT} =0V | 10 | pF |
| CO | Output Capacitance | V _{IN/OUT} =0V | 15 | pF |

1. This parameter is guaranteed but not 100% tested.

TRUTH TABLE

| \overline{CE} | \overline{OE} | MODE | OUTPUT | POWER DISSIPATION MODE |
|-----------------|-----------------|--------------|-----------|------------------------|
| H | X | Not Selected | High-Z | Standby |
| L | H | Not Selected | High-Z | Active |
| L | L | Selected | D_{OUT} | Active |

OUTPUT SELECTION MODE

| A_{-1} | BYTE | O_0 to O_7 | O_8 to O_{14} | O_{15} |
|----------|------|-------------------|-------------------|----------|
| X | H | D_0 to D_7 | D_8 to D_{14} | D_{15} |
| L | L | D_0 to D_8 | High-Z | A_{-1} |
| H | L | D_8 to D_{15} | High-Z | A_{-1} |

AC TEST CONDITIONS

| | |
|---------------------------|---------------------------------|
| Input Pulse Levels | 0.6 to 2.4V |
| Input Rise and Fall Times | $t_R = 5$ ns |
| Timing Measurement Level | $V_{IL} = 0.8V$ $V_{IH} = 2.2V$ |
| Reference | $V_{OL} = 0.8V$ $V_{OH} = 2.2V$ |
| Output Load | 1 TTL Gate and 100pF |

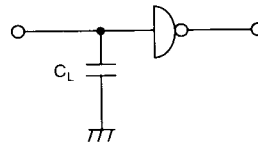


Figure 1. Output Load Circuit

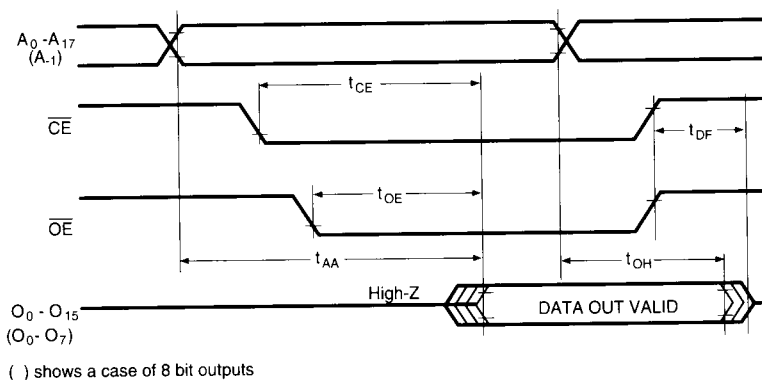
AC ELECTRICAL CHARACTERISTICS (over the operating range)

| PARAMETER NAME | PARAMETER | TEST CONDITION | MS318003-20 | | UNIT |
|----------------|----------------------------------|--|-------------|------|------|
| | | | MIN. | MAX. | |
| t_{AA} | Chip Access Time | $\overline{CE} = \overline{OE} = V_{IL}$ | - | 200 | ns |
| t_{CE} | Chip Enable Access Time | $\overline{OE} = V_{IL}$ | - | 200 | ns |
| t_{OE} | Output Enable Access Time | Note 1 | - | 80 | ns |
| t_{DF} | Output Disable | Note 2 | - | 60 | ns |
| t_{OH} | Output Hold After Address Change | $\overline{CE} = \overline{OE} = V_{IL}$ | 0 | - | ns |

Note 1: Maximum \overline{OE} delay which does not affect t_{AA} is $t_{AA} - t_{OE}$

Note 2: t_{DF} is specified by either of \overline{CE} or \overline{OE} changing to HIGH earlier.

TIMING DIAGRAMS



MS318003

ORDERING INFORMATION

| SPEED (ns) | ORDERING PART NUMBER | PACKAGE REFERENCE NO. | TEMPERATURE RANGE |
|------------|----------------------|-----------------------|-------------------|
| 200 | MS318003-20PC | P42-1 | 0°C to +70°C |
| 200 | MS318003-20QC | Q64-1 | 0°C to +70°C |